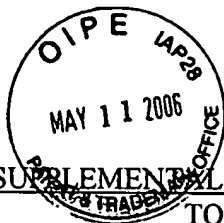


Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 251154US2SRDX		SERIAL NO. New Application	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Toru TOJO, et al.			
				FILING DATE Herewith		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
IA	AA	5,572,598	11/05/96	Mark J. WIHL, et al.			
IA	AB	5,563,702	10/08/96	David G. EMERY, et al.			
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
					YES	NO	
IA	AO	2002-501194	01/15/02	Japan		X	
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW	Yasutaka MORIKAWA, et al., "PERFORMANCE OF CELL-SHIFT DEFECT INSPECTION TECHNIQUE", Proceedings of SPIE, Photomask and X-Ray Mask Technology IV, Vol. 3096, 1997, pgs. 404 - 414.					
	AX						
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner /Isiaka Akanbi/					Date Considered 05/26/2006		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							



SUPPLEMENTAL INFORMATION CITED BY APPLICANTS THAT MAY BE MATERIAL
TO THE PROSECUTION OF THE SUBJECT APPLICATION

Applicants: B. Dorfman et al. Attorney Docket No.: 121976
Application No.: 10/809,049 Art Unit: 3661 / Confirmation No.: 5782
Filed: March 24, 2004 Examiner: Y. Beaulieu
Title: SYSTEM AND METHOD FOR AUTOMATICALLY COLLECTING
IMAGES OF OBJECTS AT GEOGRAPHIC LOCATIONS AND
DISPLAYING SAME IN ONLINE DIRECTORIES

U.S. PATENT DOCUMENTS

*Examiner Initials	Cite No.	Document No.	Kind Code	Date (mm/dd/yyyy)	Name
IA	U2	6,363,161	B2	03/26/2002	Laumeyer et al.
IA	U3	6,449,384	B2	09/10/2002	Laumeyer et al.
IA	U4	6,625,315	B2	09/23/2003	Laumeyer et al.

FOREIGN PATENT DOCUMENTS

None

OTHER INFORMATION

(Including Author, Title, Date, Pertinent Pages, Etc.)

None

Examiner

Date Considered

/Isiaka Akanbi/

05/26/2006

*Examiner: Initial if reference considered, whether or not citation is in conformance with M.P.E.P. § 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicants.

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